## **U. S. PATENT DOCUMENTS**

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE

## FOREIGN PATENT DOCUMENTS

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EXAMINER		AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.	
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EXAMINER	RAYMOND	PHAN	DATE CONSIDERED 10 -26-07
		whether or not citation is in co	formance with M.P.E.P. 609; draw line through citation if not in conformance and

<sup>\*</sup> English language abstract provided.
\*\*Corresponding PCT Patent No. WO 9854872 provided.